

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	86	(MEMS) and (mask\$2) and (topological)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:14
L2	0	(MEMS) same (mask\$2)-same (topological)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:13
L3	10	(MEMS) and ((mask\$2) same (topological))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:15
S1	1088	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:17
S2	780	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 11:36
S3	0	(716/19).ccls. and (MEMS) and (mask) and (topological adj description)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:19
S4	0	(716/21).ccls. and (MEMS) and (mask) and (topological adj description)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:20
S5	0	("716"/\$).ccls. and (MEMS) and (mask) and (topological adj description)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:20
S6	0	(MEMS) and (mask) and (topological adj description)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:20
S7	0	(MEMS) and (masks) and (topological adj description)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:20

S8	6024	(MEMS) and (mask\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:21
S9	1223	(MEMS) same (mask\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:21
S10	13	("716"/\$).cccls. and (MEMS) same (mask\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:37
S11	2	("716"/\$).cccls. and (MEMS) same (mask\$2) and (topology)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:41
S12	38	(MEMS) same (mask\$2) and (topology)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:46
S13	0	(MEMS) same (mask\$2) and (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:46
S14	0	(MEMS) and (mask\$2) and (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:46
S15	0	(MEMS) and (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:46
S16	0	(mask\$2) same (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:47
S17	15	(mask\$2) and (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:49

S18	0	("716"/\$.ccls. and (mask\$2) and (topology adj tree)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:47
S19	18	(mask\$2) and (topology adj graph)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:49
S20	0	("717"/\$.ccls. and (mask\$2) and (topology adj graph)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:49
S21	1	("716"/\$.ccls. and (mask\$2) and (topology adj graph)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:52
S22	0	("716"/\$.ccls. and (MEMS) and (mask\$2) and (topology adj graph)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 12:52
S23	1	(MEMS) and (mask\$2) and (topology adj graph)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 13:07

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